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Application/Control No.	Applicant(s)/Patent under Reexamination
10/736,605	HIROSE ET AL.
Examiner	Art Unit
Thien F. Tran	2811

SEARCHED					
Class	Subclass	Date	Examiner		
438	181, 197, 287	6/2/2006	π		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH (INCLUDING SEAF		)
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